

### Maximum Ratings (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units	
Drain-Source Voltage			$V_{DSS}$	40	V	
Gate-Source Voltage				V <sub>GSS</sub>	±20	V
Continuous Drain Current (Note 6)	V <sub>GS</sub> = 10V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I <sub>D</sub>	5.2 4.1	А
Continuous Drain Current (Note 6)	V <sub>GS</sub> = 4.5V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I <sub>D</sub>	4.3 3.4	А
Continuous Drain Current (Note 7)	V <sub>GS</sub> = 10V	Steady State	$T_A = +25$ °C $T_A = +70$ °C	I <sub>D</sub>	7.0 5.6	А
Continuous Drain Current (Note 7)	V <sub>GS</sub> = 4.5V	Steady State	$T_A = +25$ °C $T_A = +70$ °C	I <sub>D</sub>	5.8 4.7	А
Pulsed Drain Current (Note 8)				I <sub>DM</sub>	20	А

# Thermal Characteristics ( $@T_A = +25^{\circ}C$ , unless otherwise specified.)

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 6)	$P_{D}$	1.42	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = +25°C (Note 5)	$R_{ heta JA}$	88	°C/W
Total Power Dissipation (Note 7)	$P_{D}$	2.6	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = +25°C (Note 6)	$R_{ heta JA}$	48	°C/W
Operating and Storage Temperature Range	$T_{J_i}T_{STG}$	-55 to +150	°C

#### Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

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Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 9)	1		1	1			
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	_	_	V	$V_{GS} = 0V$ , $I_D = 10mA$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1	μΑ	$V_{DS} = 40V$ , $V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 9)							
Gate Threshold Voltage	$V_{GS(th)}$	1.6	2.4	3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
On-state drain current	I <sub>D(ON)</sub>	20	_	_	Α	$V_{GS} = 10V$ , $V_{DS} = 5A$	
Static Drain-Source On-Resistance	Б	_	19	31	mΩ	$V_{GS} = 10V, I_D = 6A$	
Static Drain-Source On-Resistance	R <sub>DS (ON)</sub>	_	44	50		$V_{GS} = 4.5V, I_D = 5A$	
Forward Transfer Admittance	Y <sub>fs</sub>	_	11	_	S	$V_{DS} = 5V, I_{D} = 6A$	
Diode Forward Voltage	V <sub>SD</sub>	_	0.74	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 10)							
Input Capacitance	C <sub>iss</sub>	_	945	_	pF	.,	
Output Capacitance	Coss	_	69	_	pF	$V_{DS} = 20V, V_{GS} = 0V,$ - f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	58	_	pF	1 = 1.0WI 12	
Gate Resistance	$R_{g}$	_	1.45	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Qg	_	8.4	_	nC	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 20V, I <sub>D</sub> = 12A	
Total Gate Charge (V <sub>GS</sub> = 10V)	Qg	_	18.6	_	nC		
Gate-Source Charge	Qgs	_	3.3	_	nC		
Gate-Drain Charge	Q <sub>gd</sub>	_	2.2	_	nC		
Turn-On Delay Time	T <sub>D(on)</sub>	_	6.4	_	ns		
Turn-On Rise Time	Tr	_	9.7	_	ns	$V_{GS} = 10V, V_{DS} = 20V,$ $R_{L} = 1.6\Omega, R_{G} = 3\Omega$	
Turn-Off Delay Time	T <sub>D(off)</sub>	_	19.8	_	ns		
Turn-Off Fall Time	T <sub>f</sub>	_	3.1	_	ns		

Notes: 6. Device mounted on FR-4 PCB, with minimum recommended pad layout. The value in any given application depends on user's specific board design.

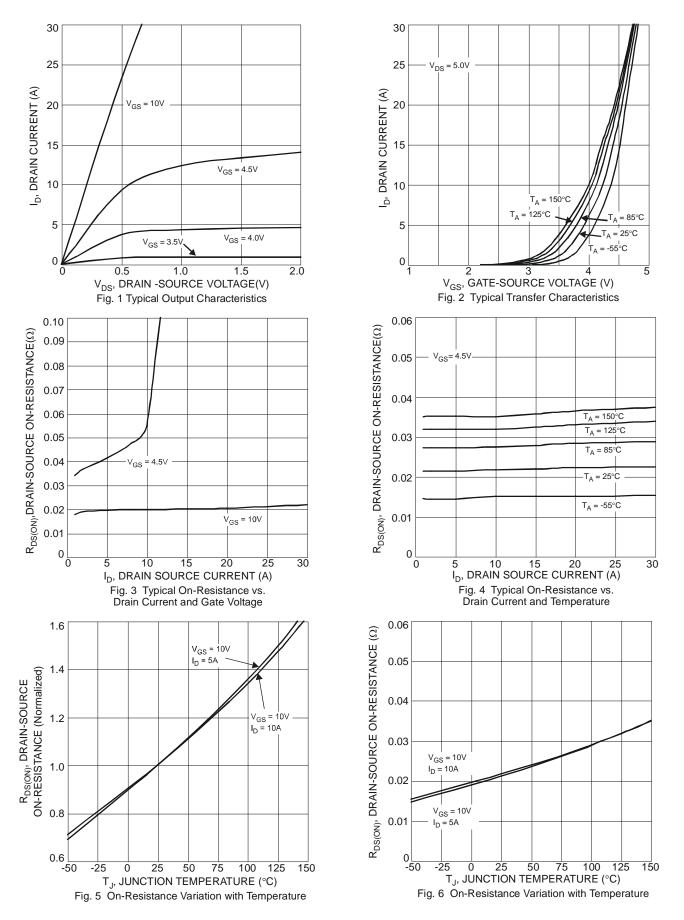
<sup>7.</sup> Device mounted on 1" x 1" FR-4PCB with high coverage 1 oz. Copper, single sided.

<sup>8.</sup> Repetitive rating, pulse width limited by junction temperature.

<sup>9.</sup> Short duration pulse test used to minimize self-heating effect.

<sup>10.</sup> Guaranteed by design. No subject to production testing.







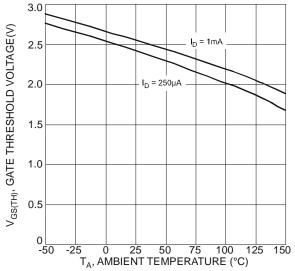
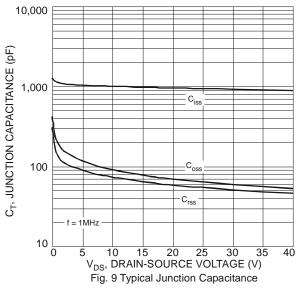
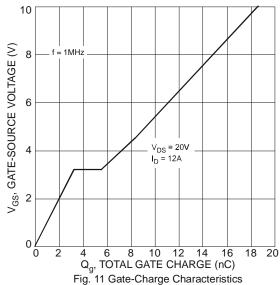
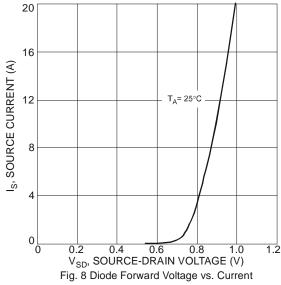


Fig. 7 Gate Threshold Variation vs. Ambient Temperature







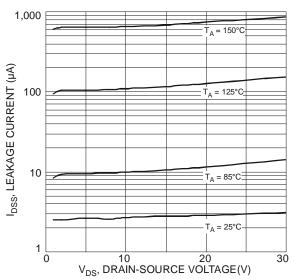
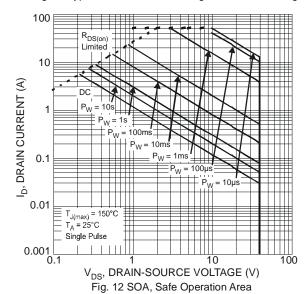


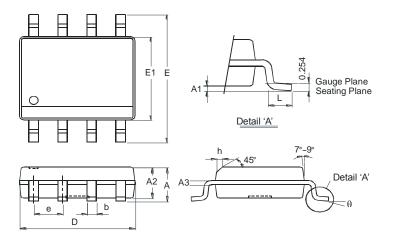
Fig. 10 Typical Drain-Source Leakage Current vs. Voltage





### **Package Outline Dimensions**

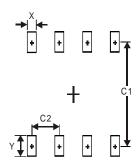
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8				
Dim	Min	Max		
Α	-	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
A3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
Е	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h	-	0.35		
L	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

## **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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